

Test Beam Characterisation of stitched CMOS Strip Sensors

Naomi Davis on behalf of the CMOS Strips Collaboration

12th edition of the Beam Telescopes and Test Beams Workshop

April 19th, Edinburgh UK

HELMHOLTZ

tu technische universität
dortmund

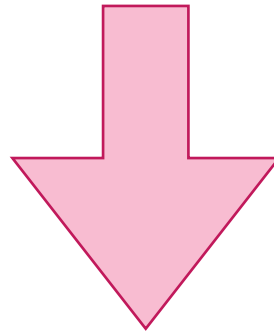
Fachhochschule
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Single-Vendor Problem

- Silicon sensors have become **indispensable** in high energy physics.
- ... only available from **few foundries**

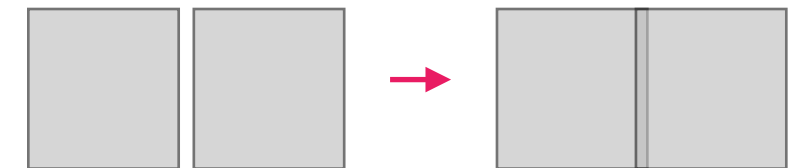
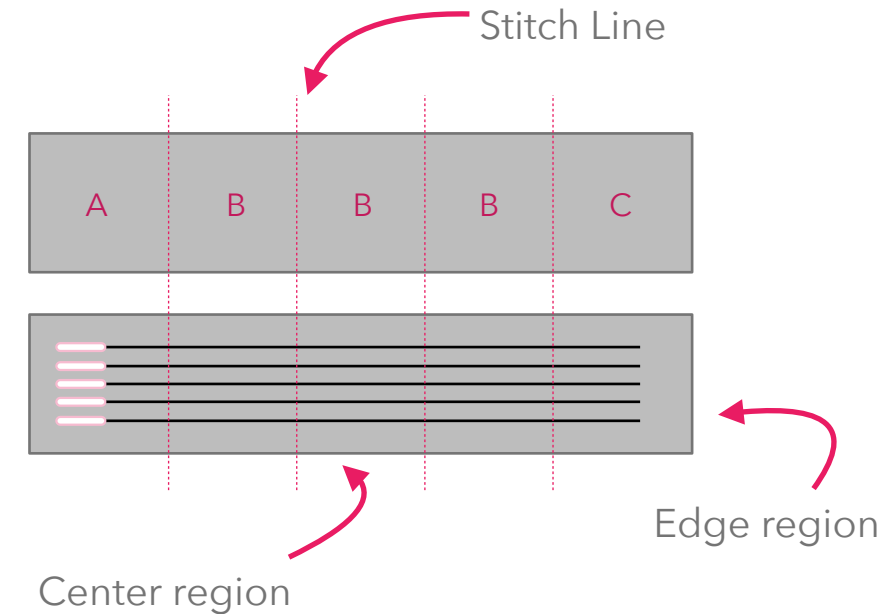
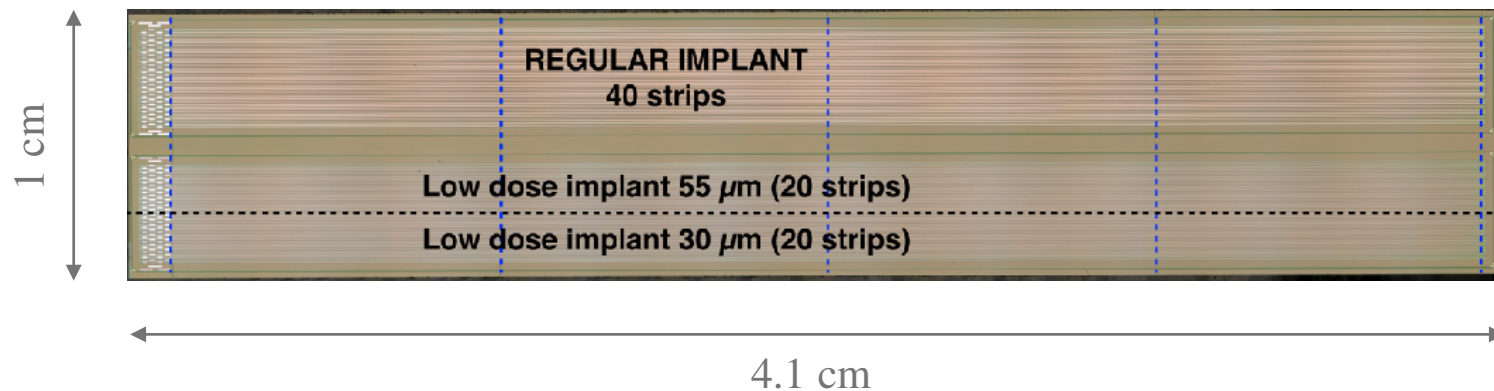


Alternative vendors ?

- Vendor diversification through standardised **industrial CMOS** process
- Fast, cheap and large-scale production

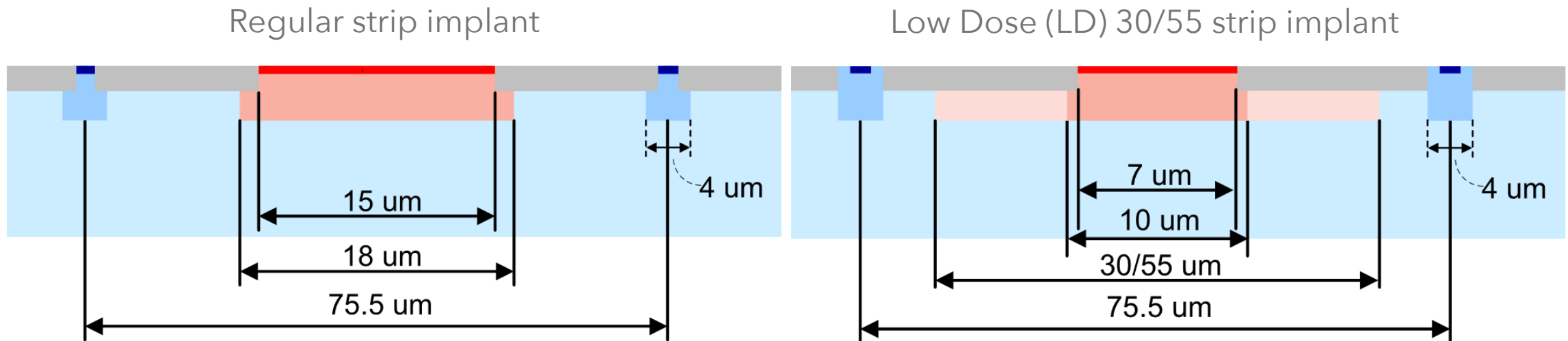
CMOS Strip Sensors

- n-in-p sensor, **150 nm** LFoundry technology
- **$150 \pm 10 \text{ um}$** thickness, **75.5 um** strip pitch
- Different formats through **stitching** technique



CMOS Strip Sensors

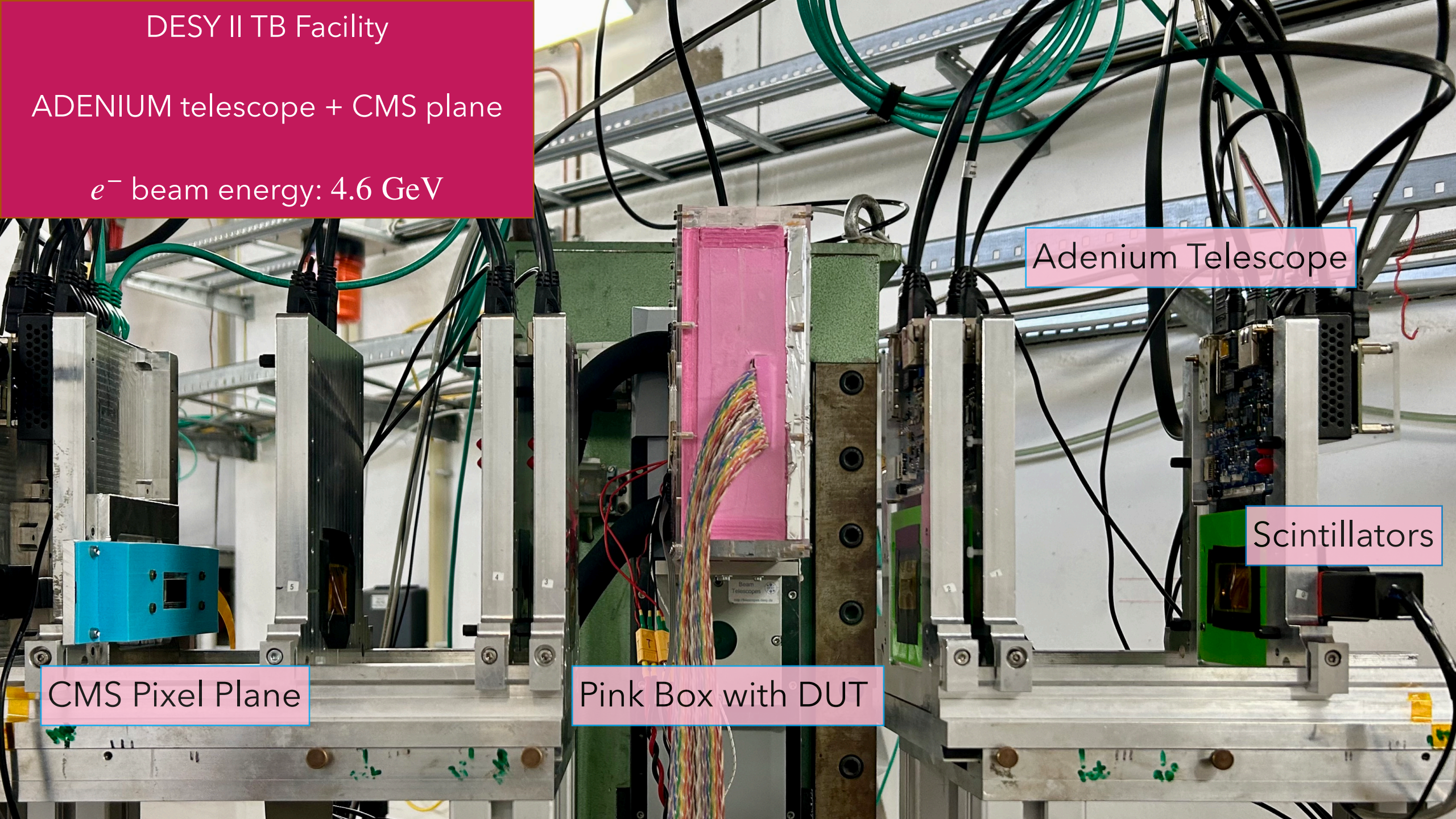
- Strip-implant varies in width and doping concentration



DESY II TB Facility

ADENIUM telescope + CMS plane

e^- beam energy: 4.6 GeV



Adenium Telescope

Scintillators

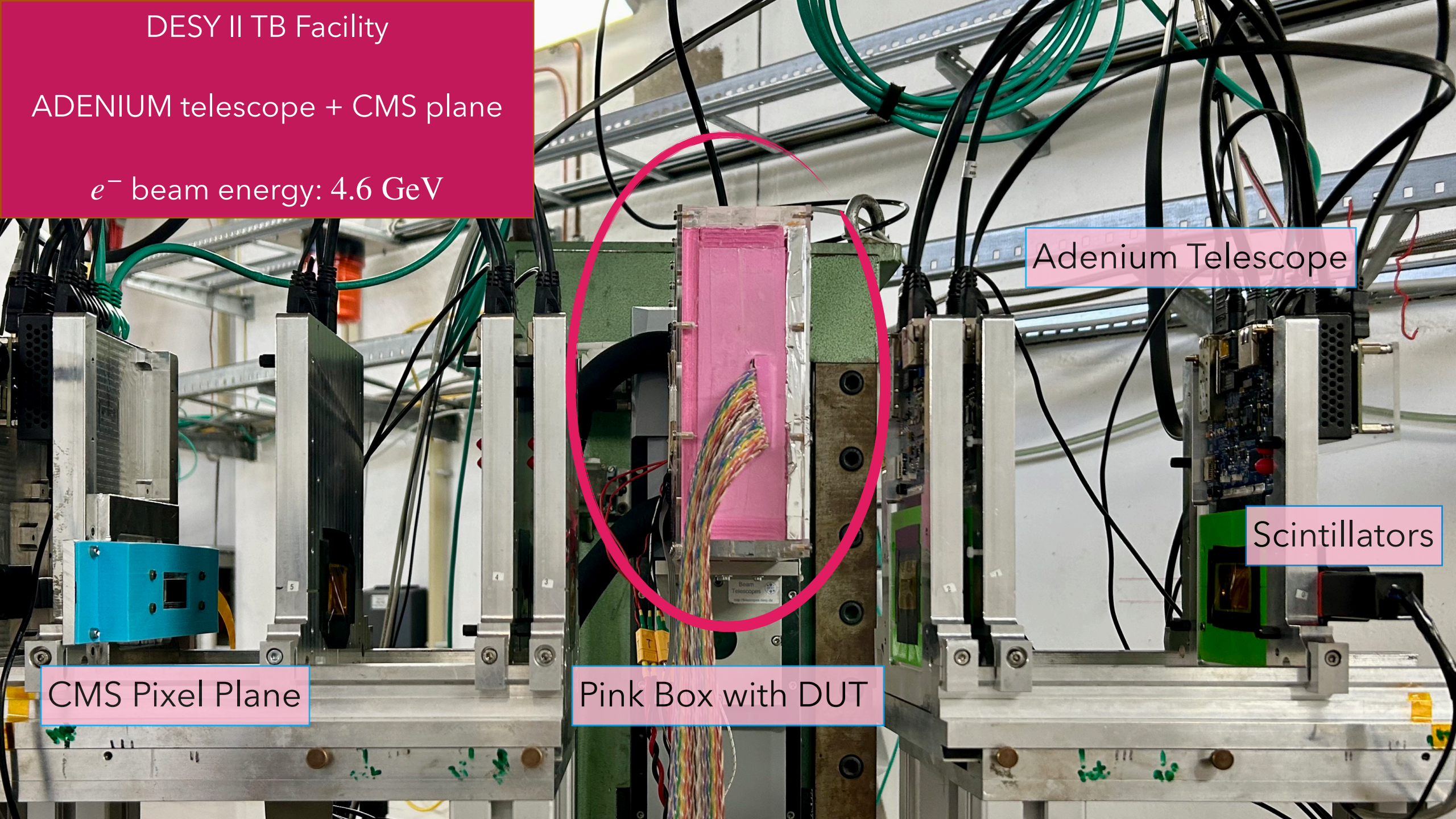
CMS Pixel Plane

Pink Box with DUT

DESY II TB Facility

ADENIUM telescope + CMS plane

e^- beam energy: 4.6 GeV



Adenium Telescope

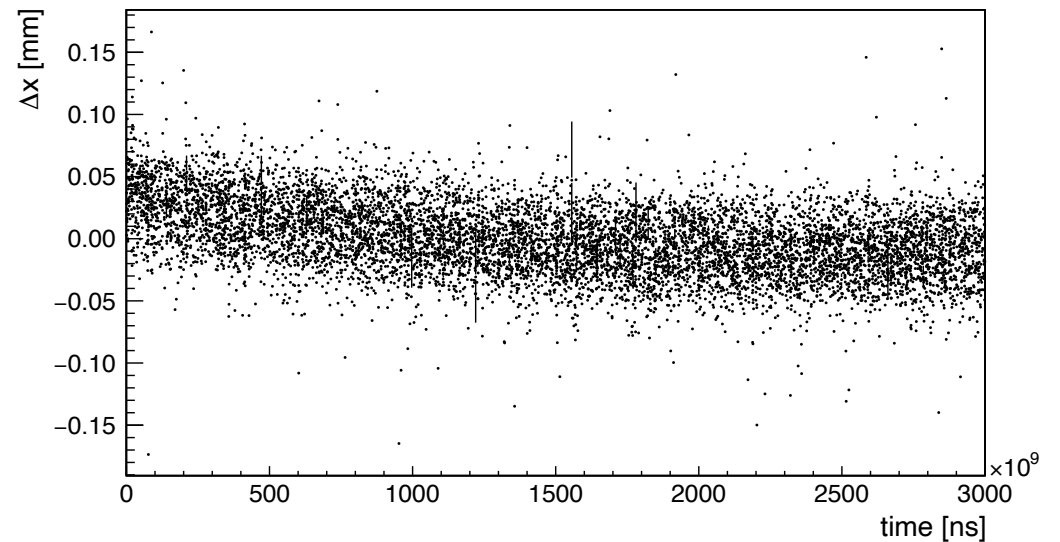
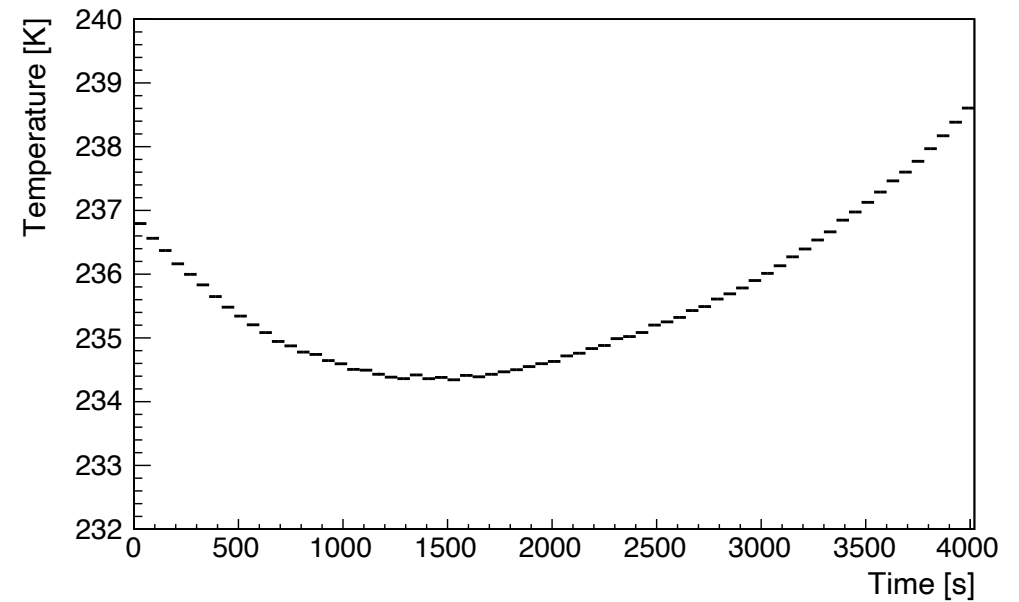
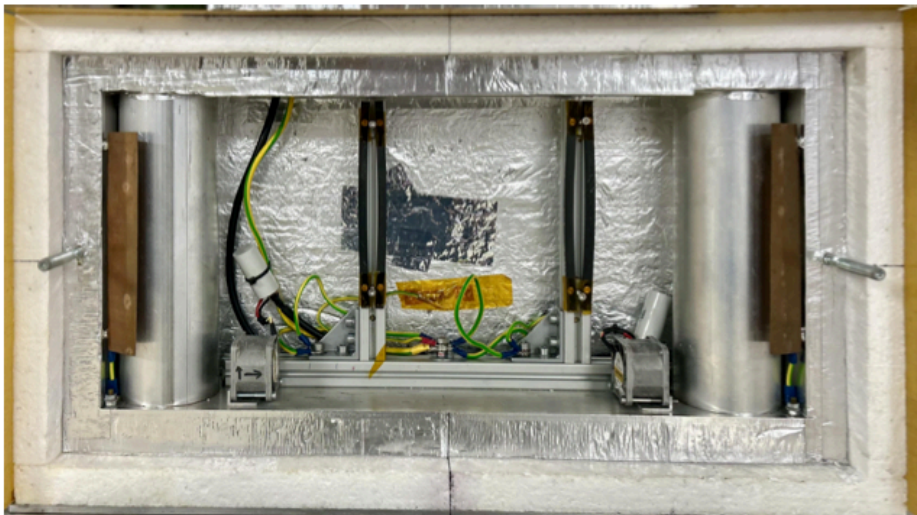
Scintillators

CMS Pixel Plane

Pink Box with DUT

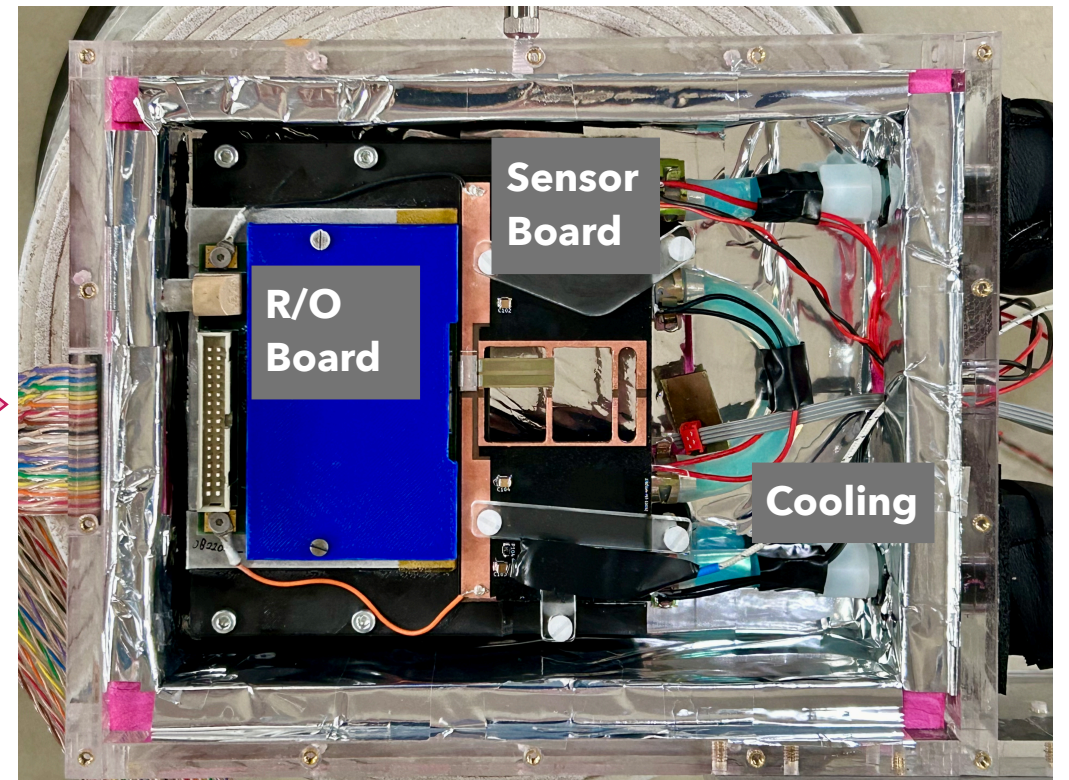
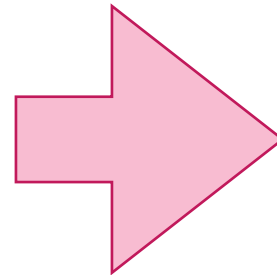
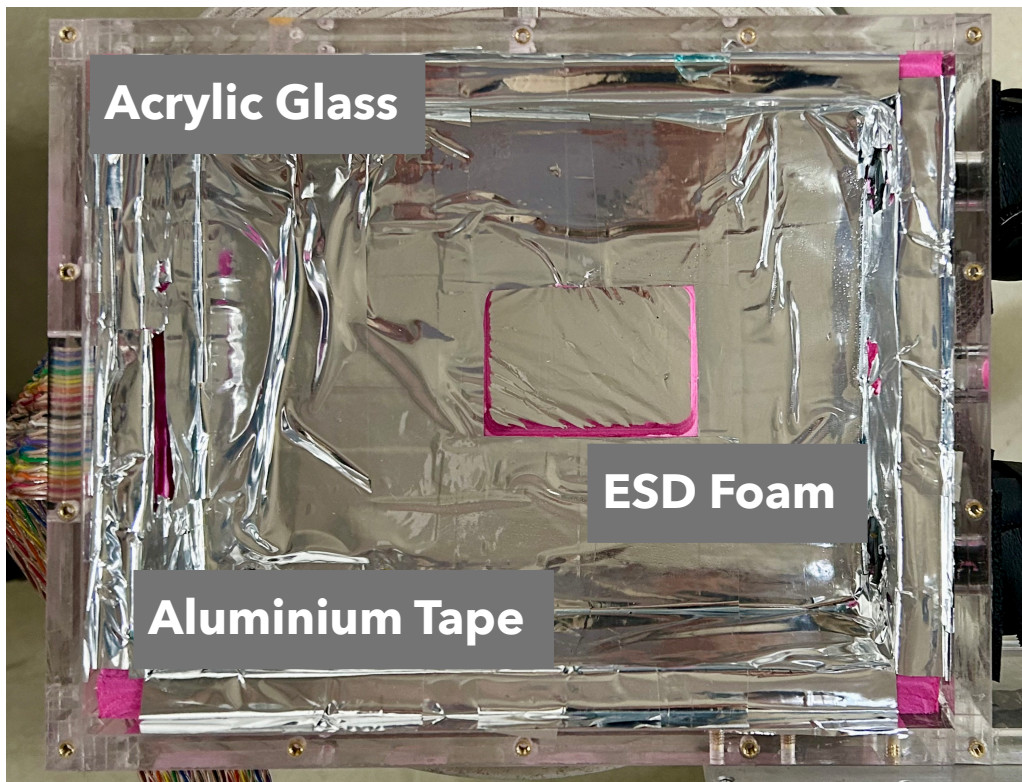
DUT Cooling – ITk Box

- Cooling with **dry ice** pellets to -45°C
- Limited **run time** of 1.5h
- Temperature and **position** fluctuations



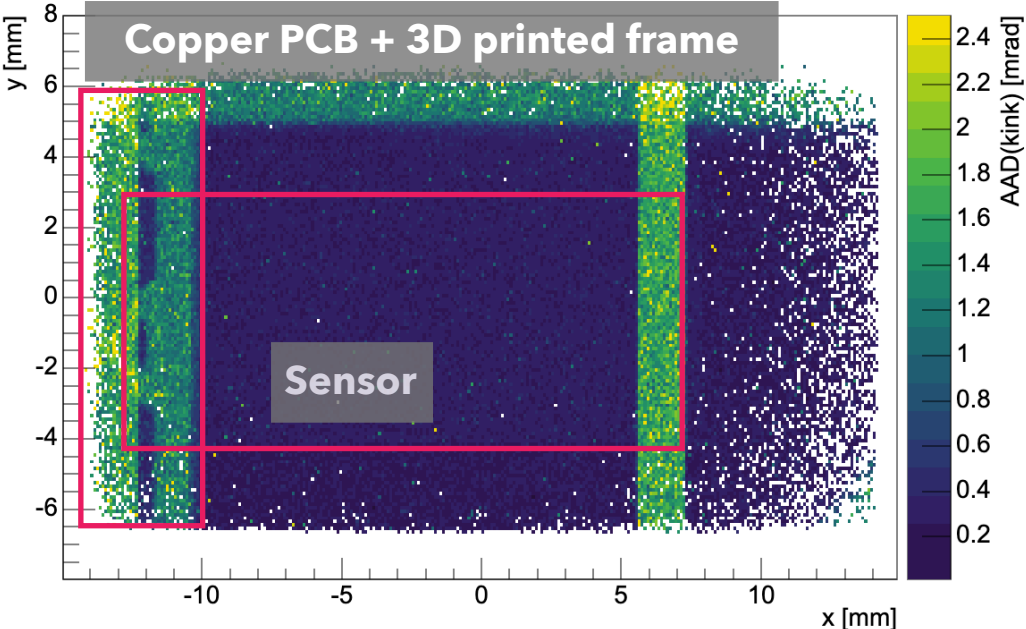
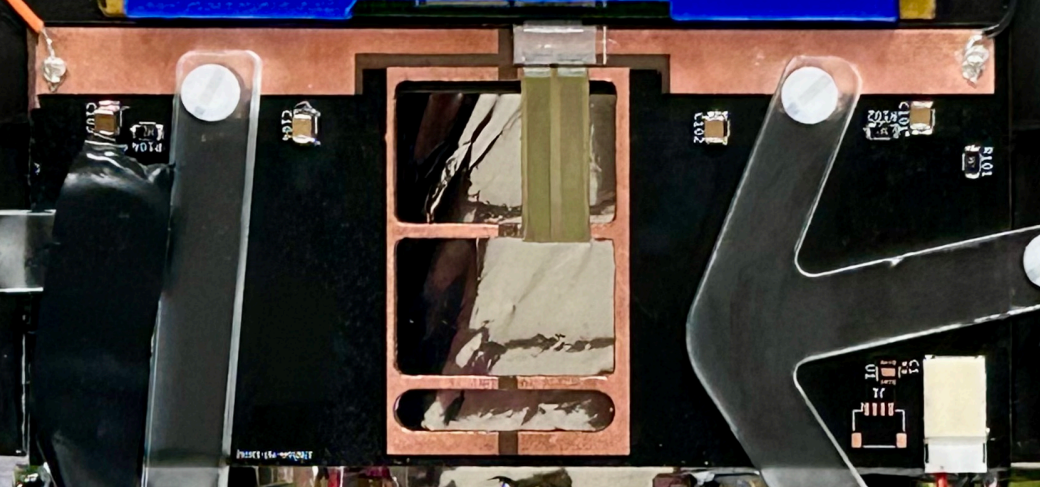
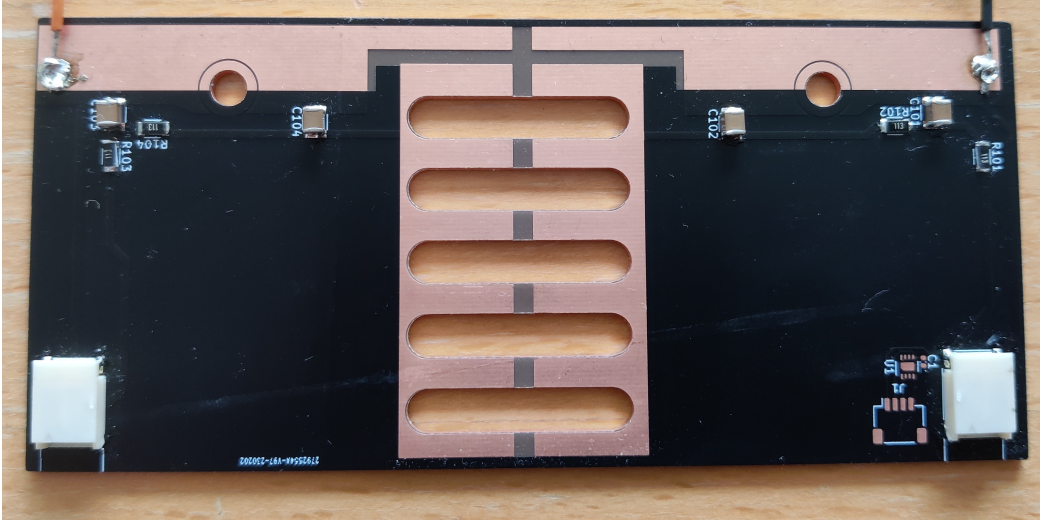
DUT Cooling – 'Pink' Box

- Reduced box dimensions
- Cooling with **stacked Peltier elements** connected to chiller

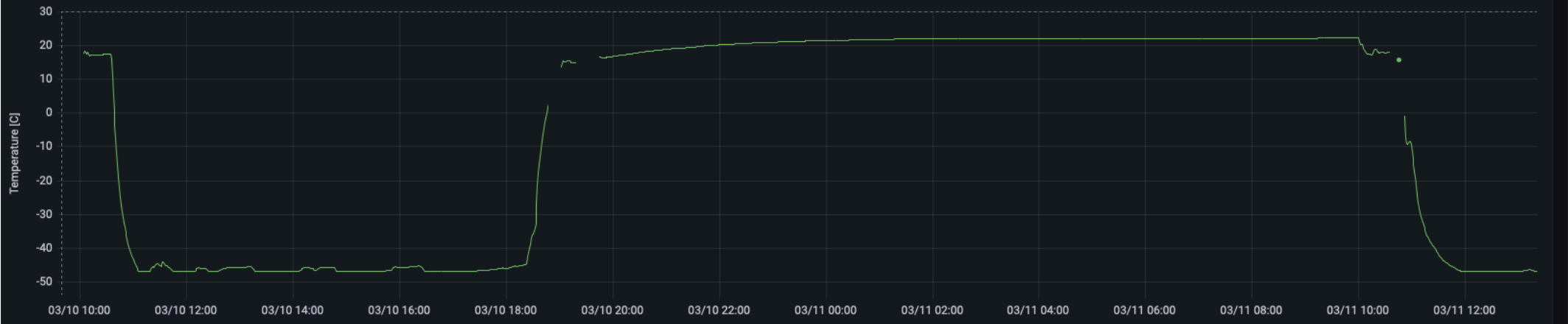


DUT Cooling – ‘Pink’ Box

- Sensor held by copper PCB (cooling)
- Reduced material budget



DUT Cooling – 'Pink' Box



Temperature in ITk Box (on sensor board)



Temperatur in Pink Box (air)

In-Strip Mean Absolute Deviation (MAD)

MAD within the strip @threshold[SNR] = 5

Unirradiated Short
Sample

@100V bias

- Hit position residual
- PCB support visible

$$MAD = \frac{\sum |x_{track} - x_{cluster}|}{n}$$

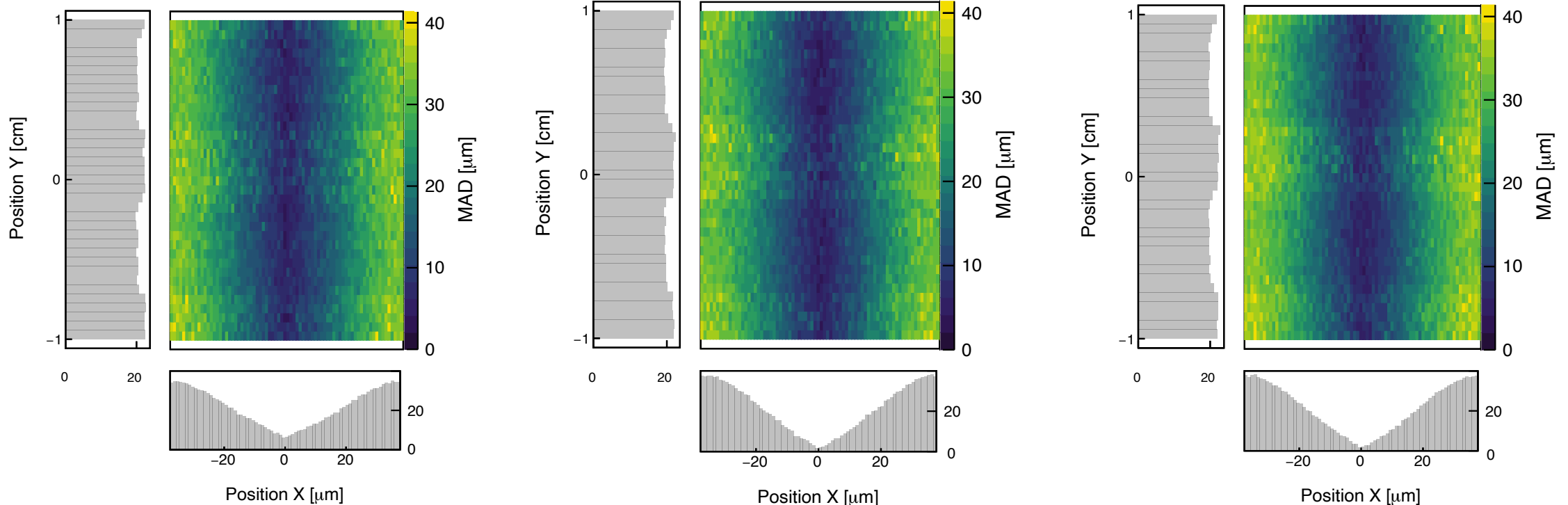


Regular

LD 55

LD 30

Stitching
→



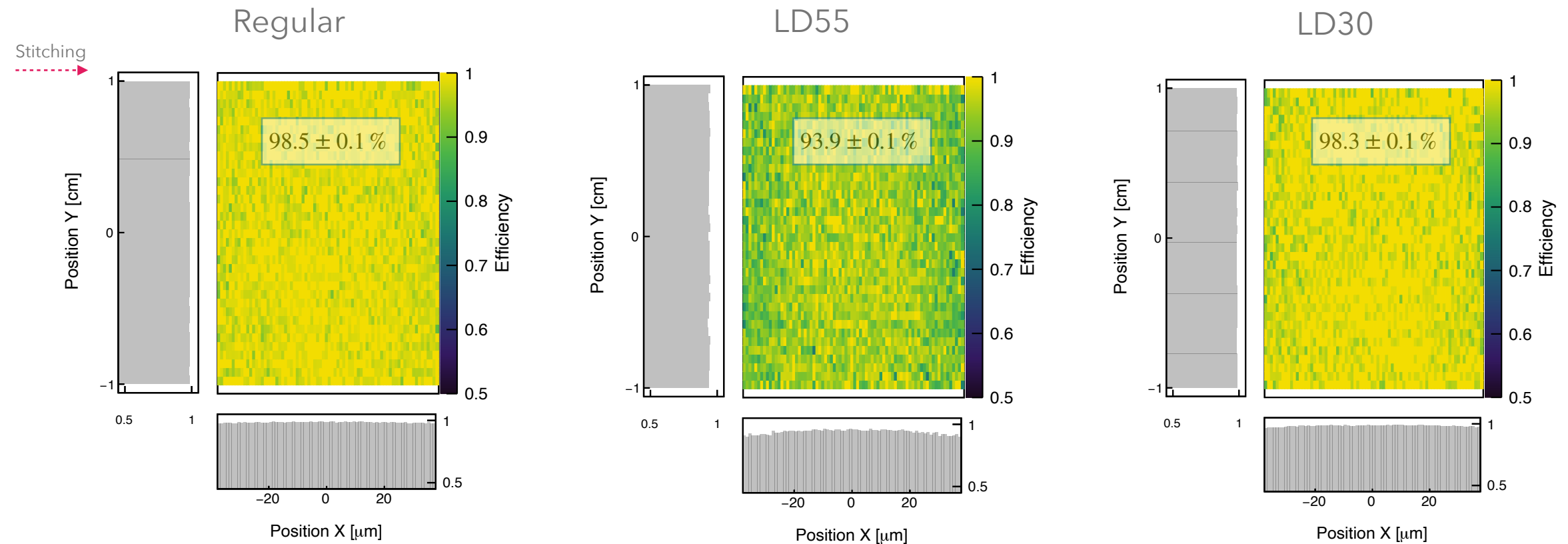
In-Strip Hit Detection Efficiency

Efficiency within the strip @threshold[SNR] = 5

Unirradiated Short
Sample

@100V bias

- Homogeneous efficiency along strip length



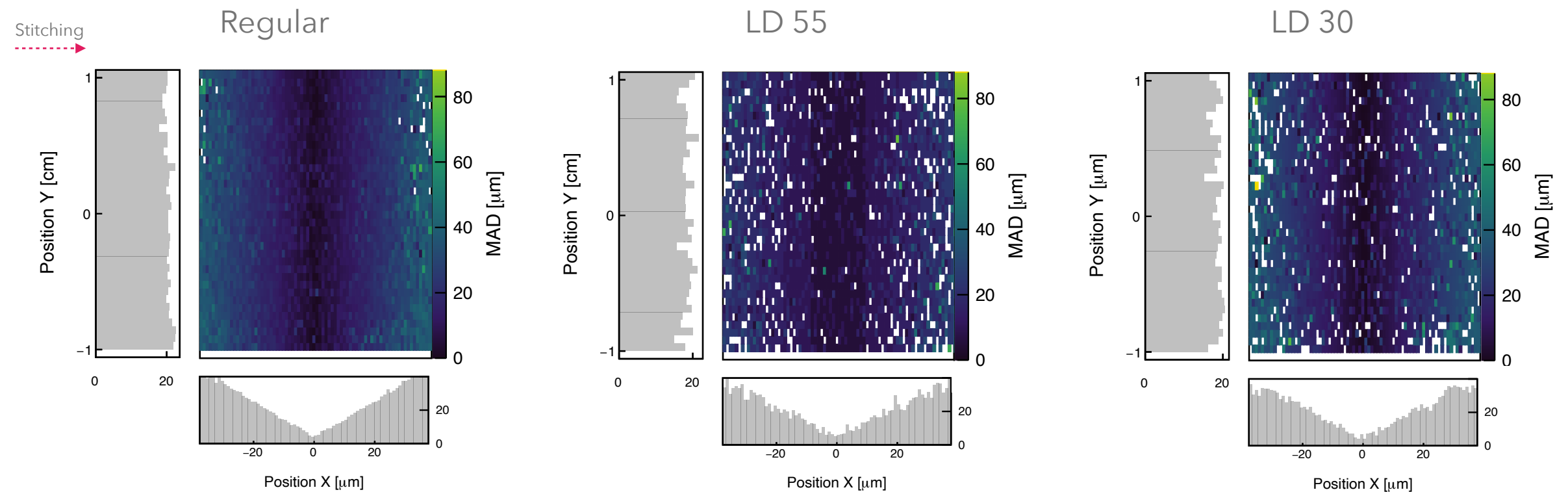
In-Strip Mean Absolute Deviation (MAD)

MAD within the strip @threshold[SNR] = 5

Neutron Irradiated Short Sample

1e16 n_{eq}/cm² @500V bias

- Hit position residual
$$\text{MAD} = \frac{\sum |x_{\text{track}} - x_{\text{cluster}}|}{n}$$
- Depreciated resolution towards strip edges (no full depletion)



In-Strip Hit Detection Efficiency

Efficiency within the strip @threshold[SNR] = 5

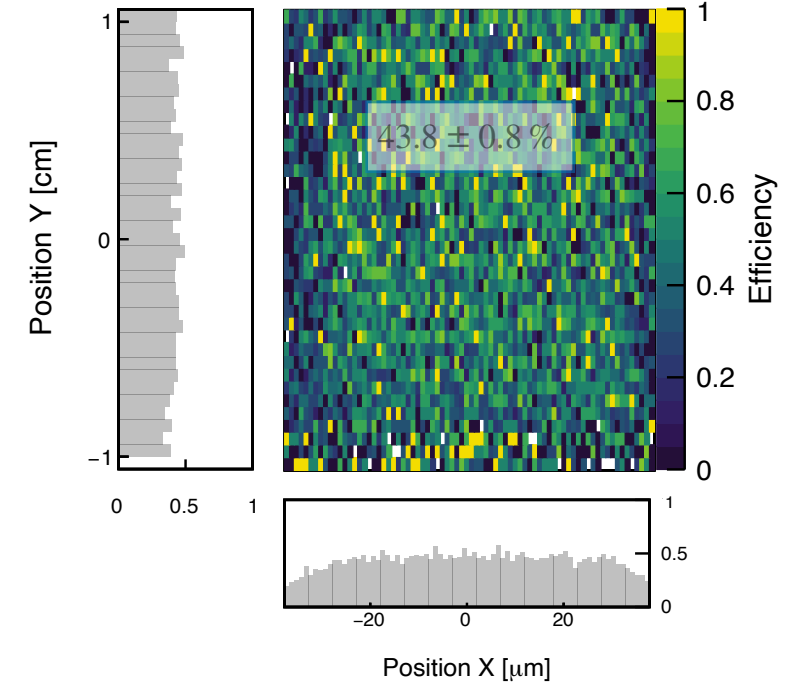
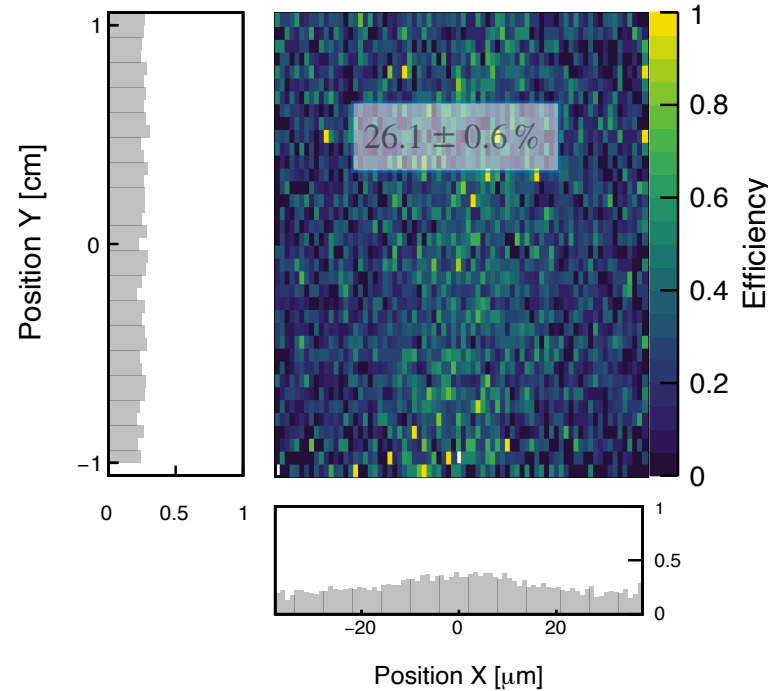
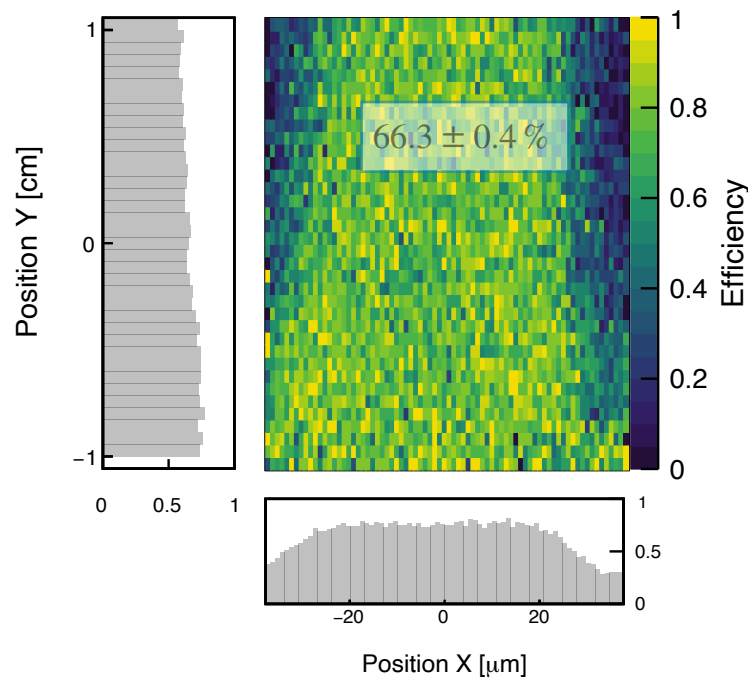
Neutron Irradiated Short Sample

$1e16$ n_{eq}/cm² @500V bias

- Strong efficiency decrease (no full depletion)
- No stitching effect at high fluences

LD 55

Stitching
→



Conclusion & Outlook

What we have learned and what's next ...

- **Stitching** does not impact resolution and hit detection efficiency!
 - Efficiency drop for **LD designs and irradiated** samples
 - Improved setup for more **efficient data taking**
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- Further Investigations:
 - Comparison to **proton** irradiation, charge calibration
 - **Active** sensor submission under discussion

Thank you, Questions?

Naomi Davis, Jan-Hendrik Arling, Marta Baselga, Leena Diehl, Jochen Dingfelder,
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The measurements leading to these results have been performed at the Test Beam Facility at DESY Hamburg (Germany), a member of the Helmholtz Association (HGF).